

# STGW35HF60WD

### 35 A, 600 V ultra fast IGBT

### Features

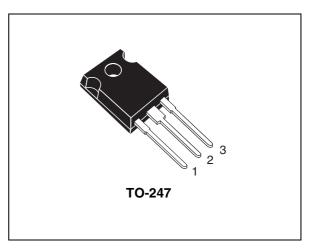
- Improved E<sub>off</sub> at elevated temperature
- Minimal tail current
- Low conduction losses
- V<sub>CE(sat)</sub> classified for easy parallel connection
- Ultra fast soft recovery antiparallel diode

### **Applications**

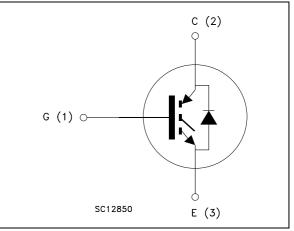
- Welding
- High frequency converters
- Power factor correction

### Description

The "HF" family is based on a new advanced planar technology concept to yield an IGBT with more stable switching performance ( $E_{off}$ ) versus temperature, as well as lower conduction losses. The "W" series is a subset of products tailored to high switching frequency operation (over 100 kHz).



#### Figure 1. Internal schematic diagram



#### Table 1. Device summary

| Order code   | Marking <sup>(1)</sup> | Package | Packaging |
|--------------|------------------------|---------|-----------|
|              | GW35HF60WDA            |         |           |
| STGW35HF60WD | GW35HF60WDB            | TO-247  | Tube      |
|              | GW35HF60WDC            |         |           |

1. Collector-emitter saturation voltage is classified in group A, B and C, see *Table 5: VCE(sat) classification*. STMicroelectronics reserves the right to ship from any group according to production availability.

## 1 Electrical ratings

| Table 2. | Absolute | maximum | ratings |
|----------|----------|---------|---------|
|          | Absolute | maximum | raungə  |

| Symbol                         | Parameter   | Value       | Unit |
|--------------------------------|---|-------------|------|
| V <sub>CES</sub>               | Collector-emitter voltage ( $V_{GE} = 0$ )                    | 600         | V    |
| I <sub>C</sub> <sup>(1)</sup>  | Continuous collector current at $T_C = 25 \ ^{\circ}C$        | 60          | Α    |
| I <sub>C</sub> <sup>(1)</sup>  | Continuous collector current at $T_C = 100 \ ^{\circ}C$       | 35          | Α    |
| $I_{CL}^{(2)}$                 | Turn-off latching current                                     | 80          | Α    |
| I <sub>CP</sub> <sup>(3)</sup> | Pulsed collector current                                      | 150         | Α    |
| $V_{GE}$                       | Gate-emitter voltage  | ± 20        | V    |
| ١ <sub>F</sub>                 | Diode RMS forward current at $T_C = 25 \text{ °C}$            | 30          | А    |
| I <sub>FSM</sub>               | Surge non repetitive forward current $t_p$ = 10 ms sinusoidal | 120         | Α    |
| P <sub>TOT</sub>               | Total dissipation at $T_C = 25 \ ^{\circ}C$                   | 200         | W    |
| T <sub>stg</sub>               | Storage temperature   | - 55 to 150 |      |
| Тj                             | Operating junction temperature                                | - 55 10 150 | °C   |

1. Calculated according to the iterative formula:

$$I_{C}(T_{C}) = \frac{T_{j(max)} - T_{C}}{R_{thj-c} \times V_{CE(sat)(max)}(T_{j(max)}, I_{C}(T_{C}))}$$

2. Pulse width limited by maximum junction temperature and turn-off within RBSOA

3.  $V_{CLAMP}$  = 80% (V<sub>CES</sub>), V<sub>GE</sub> = 15 V, R<sub>G</sub> = 10  $\Omega$ , T<sub>J</sub> = 150 °C

Table 3.Thermal data

| Symbol                | Parameter                              | Value | Unit |
|-----------------------|--|-------|------|
| D                     | Thermal resistance junction-case IGBT  | 0.63  | °C/W |
| R <sub>thj-case</sub> | Thermal resistance junction-case diode | 1.5   | °C/W |
| R <sub>thj-amb</sub>  | Thermal resistance junction-ambient    | 50    | °C/W |



## 2 Electrical characteristics

 $(T_J = 25 \ ^{\circ}C \text{ unless otherwise specified})$ 

| Table 4. | Static |
|----------|--------|
|          | Julic  |

| [                    |   |   |      |      |          |          |
|----------------------|---|---|------|------|----------|----------|
| Symbol               | Parameter   | Test conditions   | Min. | Тур. | Max.     | Unit     |
| V <sub>(BR)CES</sub> | Collector-emitter<br>breakdown voltage<br>(V <sub>GE</sub> = 0) | I <sub>C</sub> = 1 mA   | 600  |      |          | V        |
| Man                  | E(sat) Collector-emitter saturation voltage                     | $V_{GE} = 15 \text{ V}, \text{ I}_{C} = 20 \text{ A}$                       |      |      | 2.5      | v        |
| V <sub>CE(sat)</sub> |   | V <sub>GE</sub> = 15V, I <sub>C</sub> = 20 A,T <sub>J</sub> = 125 °C        |      | 1.65 |          | v        |
| V <sub>GE(th)</sub>  | Gate threshold voltage  | $V_{CE} = V_{GE}, I_C = 1 \text{ mA}$                                       | 3.75 |      | 5.75     | V        |
| I <sub>CES</sub>     | Collector cut-off current $(V_{GE} = 0)$                        | V <sub>CE</sub> = 600 V<br>V <sub>CE</sub> = 600 V, T <sub>J</sub> = 125 °C |      |      | 250<br>1 | μA<br>mA |
| I <sub>GES</sub>     | Gate-emitter leakage<br>current (V <sub>CE</sub> = 0)           | V <sub>GE</sub> = ±20 V   |      |      | ± 100    | nA       |
| 9 <sub>fs</sub>      | Forward<br>transconductance                                     | V <sub>CE</sub> = 15 V <sub>,</sub> I <sub>C</sub> = 20 A                   |      | 15   |          | S        |

Table 5. V<sub>CE(sat)</sub> classification

| Symbol               | Parameter  | Group | Va   | lue  | Unit |
|----------------------|--|-------|------|------|------|
| Symbol               | Farameter  | Group | Min. | Max. | Onit |
|                      | $V_{CE(sat)}$ Collector-emitter saturation voltage $V_{GE} = 15 \text{ V}, I_C = 20 \text{ A}$ |       | 1.68 | 1.92 |      |
| V <sub>CE(sat)</sub> |  |       | 1.88 | 2.17 | V    |
|                      | VGE - 10 V, IC- 2011   | С     | 2.13 | 2.50 |      |

Table 6. Dynamic

| Symbol   | Parameter  | Test conditions   | Min. | Тур.              | Max. | Unit           |
|--|--|---|------|-------------------|------|----------------|
| C <sub>ies</sub><br>C <sub>oes</sub><br>C <sub>res</sub> | Input capacitance<br>Output capacitance<br>Reverse transfer<br>capacitance | V <sub>CE</sub> = 25 V, f = 1 MHz,<br>V <sub>GE</sub> = 0   | -    | 2400<br>235<br>50 | -    | pF<br>pF<br>pF |
| Q <sub>g</sub><br>Q <sub>ge</sub><br>Q <sub>gc</sub>     | Total gate charge<br>Gate-emitter charge<br>Gate-collector charge          | V <sub>CE</sub> = 390 V, I <sub>C</sub> = 20 A,<br>V <sub>GE</sub> = 15 V,<br><i>(see Figure 3)</i> | -    | 140<br>13<br>52   | -    | nC<br>nC<br>nC |



| Symbol  | Parameter   | Test conditions  | Min. | Тур.             | Max. | Unit             |
|---|---|--|------|------------------|------|------------------|
| t <sub>d(on)</sub><br>t <sub>r</sub><br>(di/dt) <sub>on</sub>                             | Turn-on delay time<br>Current rise time<br>Turn-on current slope  | $V_{CC} = 390 \text{ V}, I_{C} = 20 \text{ A}$<br>$R_{G} = 10 \Omega, V_{GE} = 15 \text{ V},$<br>(see Figure 2)                                      | -    | 30<br>15<br>1650 | -    | ns<br>ns<br>A/µs |
| t <sub>d(on)</sub><br>t <sub>r</sub><br>(di/dt) <sub>on</sub>                             | Turn-on delay time<br>Current rise time<br>Turn-on current slope  | $V_{CC} = 390 \text{ V}, I_C = 20 \text{ A}$<br>$R_G = 10 \Omega, V_{GE} = 15 \text{ V},$<br>$T_J = 125 \text{ °C} (see Figure 2)$                   | -    | 30<br>15<br>1600 | -    | ns<br>ns<br>A/µs |
| $t_r(V_{off}) \ t_d(_{off}) \ t_f$  | Off voltage rise time<br>Turn-off delay time<br>Current fall time | $V_{CC} = 390 \text{ V}, \text{ I}_{C} = 20 \text{ A},$<br>$R_{GE} = 10 \Omega, \text{ V}_{GE} = 15 \text{ V}$<br>(see Figure 2)                     | -    | 30<br>175<br>40  | -    | ns<br>ns<br>ns   |
| t <sub>r</sub> (V <sub>off</sub> )<br>t <sub>d</sub> ( <sub>off</sub> )<br>t <sub>f</sub> | Off voltage rise time<br>Turn-off delay time<br>Current fall time | $V_{CC} = 390 \text{ V}, I_{C} = 20 \text{ A},$<br>$R_{GE} = 10 \Omega, V_{GE} = 15 \text{ V},$<br>$T_{J} = 125 \text{ °C}$<br><i>(see Figure 2)</i> | -    | 50<br>225<br>70  | -    | ns<br>ns<br>ns   |

Table 7. Switching on/off (inductive load)

 Table 8.
 Switching energy (inductive load)

| Symbol                         | Parameter                 | Test conditions  | Min. | Тур. | Max. | Unit |
|--------------------------------|---------------------------|--|------|------|------|------|
| E <sub>on</sub> <sup>(1)</sup> | Turn-on switching losses  | $V_{CC} = 390 \text{ V}, \text{ I}_{C} = 20 \text{ A}$ |      | 290  |      | μJ   |
| E <sub>off</sub>               | Turn-off switching losses | $R_{G} = 10 \Omega, V_{GE} = 15 V,$                    | -    | 185  |      | μJ   |
| E <sub>ts</sub>                | Total switching losses    | (see Figure 4)   |      | 475  |      | μJ   |
| E <sub>on</sub> <sup>(1)</sup> | Turn-on switching losses  | $V_{CC} = 390 \text{ V}, \text{ I}_{C} = 20 \text{ A}$ |      | 420  |      | μJ   |
| E <sub>off</sub>               | Turn-off switching losses | $R_{G} = 10 \ \Omega, V_{GE} = 15 \ V,$                | -    | 350  | 530  | μJ   |
| E <sub>ts</sub>                | Total switching losses    | T <sub>J</sub> = 125 °C <i>(see Figure 4)</i>          |      | 770  |      | μJ   |

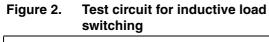
 Eon is the tun-on losses when a typical diode is used in the test circuit in *Figure 4*. If the IGBT is offered in a package with a co-pak diode, the co-pack diode is used as external diode. IGBTs and diode are at the same temperature (25 °C and 125 °C). Eon include diode recovery energy.

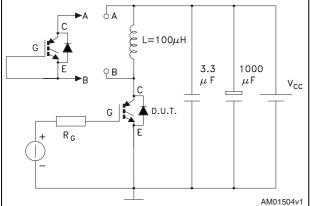
Table 9. Collector-emitter diode

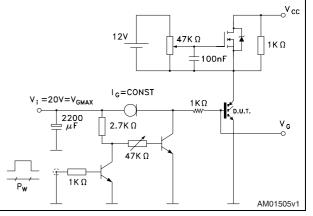
| Symbol   | Parameter  | Test conditions   | Min. | Тур.             | Max. | Unit          |
|--|--|---|------|------------------|------|---------------|
| V <sub>F</sub>   | Forward on-voltage   | I <sub>F</sub> = 20 A<br>I <sub>F</sub> = 20 A, T <sub>J</sub> = 125 °C   | -    | 1.6<br>1.3       | -    | V<br>V        |
| t <sub>rr</sub><br>Q <sub>rr</sub><br>I <sub>rrm</sub> | Reverse recovery time<br>Reverse recovery charge<br>Reverse recovery current | $I_F = 20 \text{ A}, V_R = 50 \text{ V},$<br>di/dt = 100 A/ $\mu$ s<br>(see Figure 5)   | -    | 45<br>70<br>3    | -    | ns<br>nC<br>A |
| t <sub>rr</sub><br>Q <sub>rr</sub><br>I <sub>rrm</sub> | Reverse recovery time<br>Reverse recovery charge<br>Reverse recovery current | $I_F = 20 \text{ A}, V_R = 50 \text{ V},$<br>$T_J = 125 \text{ °C}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$<br><i>(see Figure 5)</i> | -    | 90<br>240<br>5.5 | -    | ns<br>nC<br>A |



## 3 Test circuits







Gate charge test circuit

Figure 4. Switching waveform



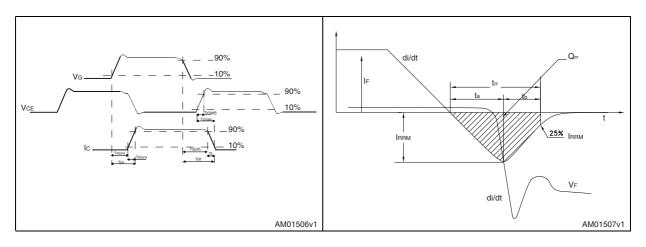


Figure 3.



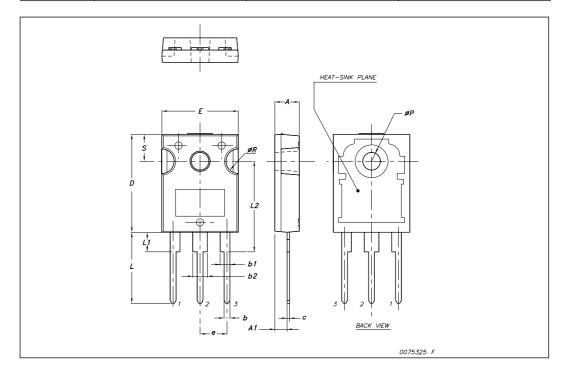
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



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|      | TO-247 Mechanical data |       |       |  |  |  |
|------|------------------------|-------|-------|--|--|--|
| Dim. |                        | mm.   |       |  |  |  |
|      | Min.                   | Тур   | Max.  |  |  |  |
| А    | 4.85                   |       | 5.15  |  |  |  |
| A1   | 2.20                   |       | 2.60  |  |  |  |
| b    | 1.0                    |       | 1.40  |  |  |  |
| b1   | 2.0                    |       | 2.40  |  |  |  |
| b2   | 3.0                    |       | 3.40  |  |  |  |
| С    | 0.40                   |       | 0.80  |  |  |  |
| D    | 19.85                  |       | 20.15 |  |  |  |
| Е    | 15.45                  |       | 15.75 |  |  |  |
| е    |                        | 5.45  |       |  |  |  |
| L    | 14.20                  |       | 14.80 |  |  |  |
| L1   | 3.70                   |       | 4.30  |  |  |  |
| L2   |                        | 18.50 |       |  |  |  |
| øP   | 3.55                   |       | 3.65  |  |  |  |
| øR   | 4.50                   |       | 5.50  |  |  |  |
| S    |                        | 5.50  |       |  |  |  |





Doc ID 15592 Rev 4

# 5 Revision history

| Date        | Revision | Changes  |
|-------------|----------|--|
| 14-Apr-2009 | 1        | Initial release.   |
| 03-Aug-2009 | 2        | Inserted dynamic parameters on <i>Table 6</i> an <i>Table 7</i><br>Document status promoted from preliminary data to datasheet |
| 02-Sep-2009 | 3        | Minor text changes throughout the document<br>Removed watermark  |
| 30-Sep-2009 | 4        | Inserted V <sub>CE(sat)</sub> grouping A, B and C (see <i>Table 5: VCE(sat)</i> classification)                                |



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